

ABSTRACT

An apparatus comprising an integrated circuit on a VLSI die, and an embedded micro-controller constructed on the VLSI die, the micro-controller adapted to monitor and control the VLSI environment to optimize the integrated circuit operation. Another embodiment of the invention is directed to a method for monitoring and controlling an integrated circuit comprising providing an embedded micro-controller on a same VLSI die as the integrated circuit, monitoring and controlling a VLSI environment of the integrated circuit with the embedded micro-controller.